

40V N-Channel Enhancement Mode Power MOSFET

Features

• 40V/190A,

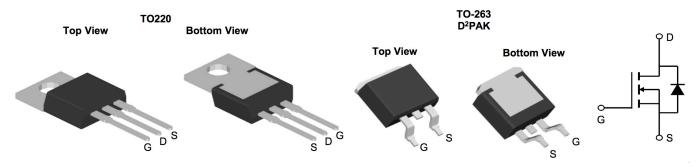
 $R_{DS (ON)} = 1.8 m\Omega(Typ.)@V_{GS} = 10V$

- 100% avalanche testedh t t d
- 175°C Operating Temperatur
- Lead Free and Green Devices Available (RoHS Compliant

- Motor Drive
- Uninterruptible Power Supplie
- DC/DC converte
- General Purpose Application







Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit				
Common Ra	atings (T _C =25°C Unless Otherwise Noted)		<u>'</u>				
$V_{\rm DSS}$	Drain-Source Voltage		40	.,			
V_{GSS}	Gate-Source Voltage		±20	V			
T_J	Maximum Junction Temperature		175	°C			
T_{STG}	Storage Temperature Range	-55 to 175	°C				
Is	Diode Continuous Forward Current	190	Α				
Mounted on Large Heat Sink							
l _{DP} ①	300μs Pulse Drain Current Tested	T _C =25°C	760	Α			
I _D ^②	T _C =25°C		190	Α			
	Continuous Drain Current(V_{GS} =10V) T_C =100°C	146					
P _D	T _C =25°C		300	\A/			
	Maximum Power Dissipation	T _C =100°C	150	W			
$R_{\scriptscriptstyle{ hetaJC}}$	Thermal Resistance-Junction to Case	0.5	°C/W				
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	62.5	°C/W				
Drain-Sourc	e Avalanche Ratings						
E _{AS}	Avalanche Energy, Single Pulsed	812	mJ				



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Electrical Characteristics (T_C=25°C Unless Otherwise Noted)

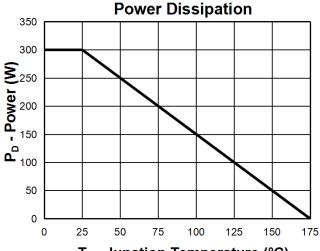
	Downston	T 10 III	,				
Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit	
Static Cha	racteristics		•	*			
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	40			V	
	Zara Cata Valtana Drain Current	V _{DS} =40V, V _{GS} =0V			1		
I _{DSS}	Zero Gate Voltage Drain Current	T _J =125°C			30	μA	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{DS}=250\mu A$	2		4	V	
I _{GSS}	Gate Leakage Current	V_{GS} =±20V, V_{DS} =0V			±100	nA	
R _{DS(ON)}	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =75A		1.8	3	mΩ	
` '	racteristics		-	-			
V _{SD}	Diode Forward Voltage	I _{SD} =75A, V _{GS} =0V			1.3	V	
trr	Reverse Recovery Time	754 11 / 11 4004/		40		ns	
Qrr	Reverse Recovery Charge	Isp=75A, dlsp/dt=100A/µs		52		nC	
Dynamic C	Characteristics ^⑤						
R_{G}	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1MHz		1.2		Ω	
C _{iss}	Input Capacitance	V _{GS} =0V,		4800			
C _{oss}	Output Capacitance	V _{DS} =20V,		950		pF	
C _{rss}	Reverse Transfer Capacitance	Frequency=1.0MHz		480			
t _{d(ON)}	Turn-on Delay Time			19			
t _r	Turn-on Rise Time	V _{DD} =20V,I _{DS} =75A,		96			
t _{d(OFF)}	Turn-off Delay Time	V_{GEN} =10V, R_{G} =2.5 Ω		70		ns	
t _f	Turn-off Fall Time			50			
Gate Char	ge Characteristics ^⑤		-	-			
Q_g	Total Gate Charge			120			
Q_{gs}	Gate-Source Charge	V_{DS} =32V, V_{GS} =10V,		34		nC	
Q_{gd}	Gate-Drain Charge	I _{DS} =75A		46		1	

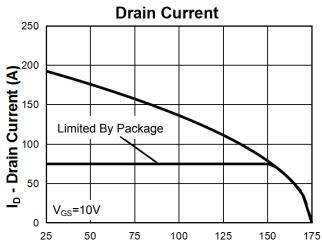
Notes:

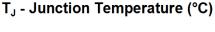
- ①Pulse width limited by safe operating area.
- ②Calculated continuous current based on maximum allowable junction temperature. The package limitation current is 75A.
- $\ \ \, \mbox{\@ifnextrack{\@model{}}{\oomega}} \ \mbox{\@model{}}{\oomega}} \ \mbox{\@model{}}{\oomega}} \ \mbox{\@model{}}{\oomega}} \ \mbox{\@model{}}{\oomega}} \ \mbox{\@model{}}{\oomega} \ \mbox{\@model{}}{\oomega}} \$
- ④Pulse test; Pulse width≤300μs, duty cycle≤2%.
- ⑤Guaranteed by design, not subject to production testing.



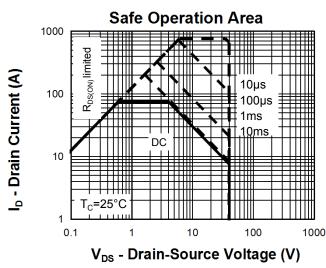
Typical Characteristics

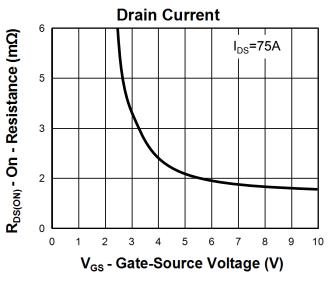




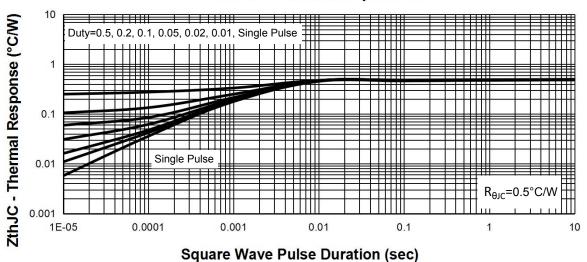






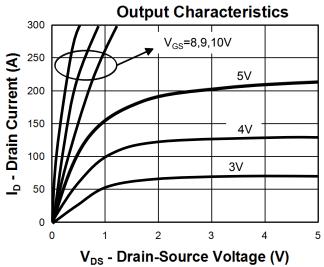


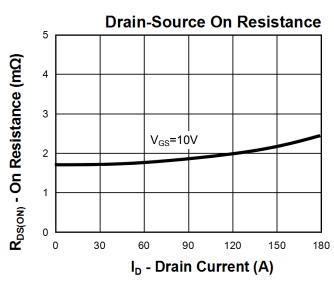
Thermal Transient Impedance

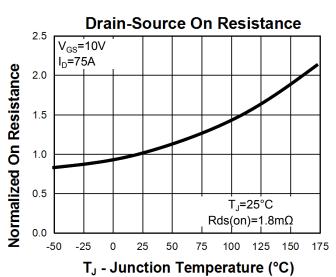


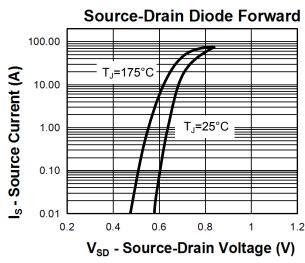


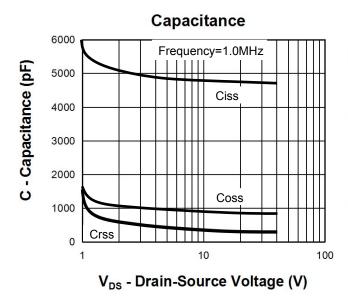
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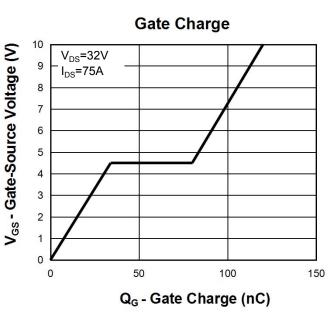






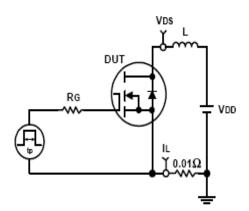


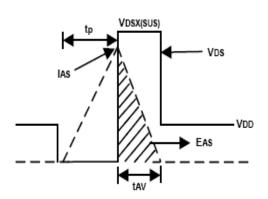




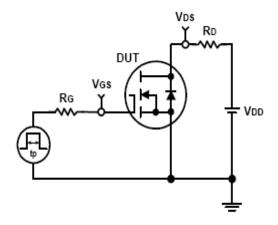


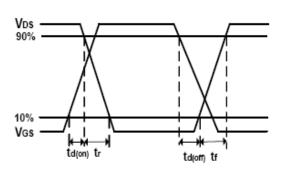
Avalanche Test Circuit and Waveforms





Switching Time Test Circuit and Waveforms

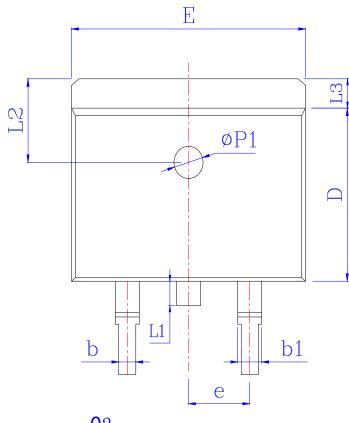


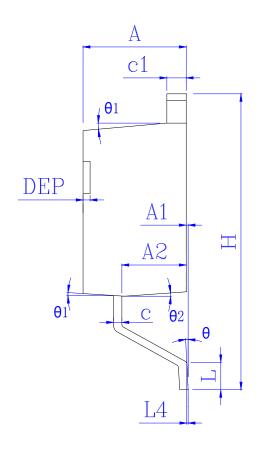


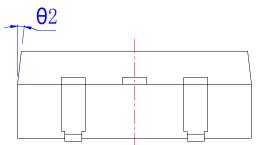


Package Information

TO263





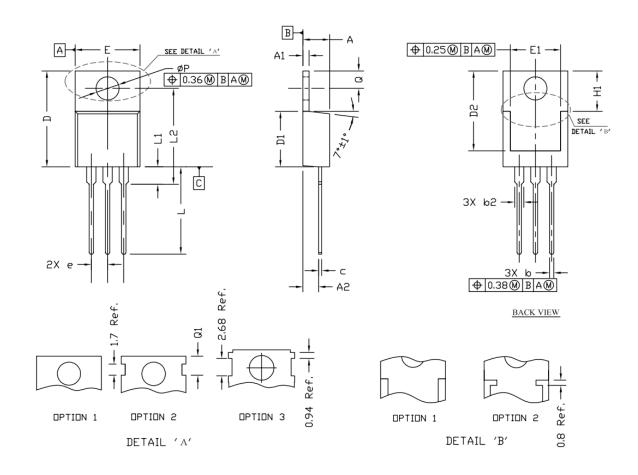


SYMBOL		MM			INCH		SYMBOL		MM			INCH	
OTMDOL	MIN	NOM	MAX	MIN	NOM	MAX	OIMDOL	MIN	NOM	MAX	MIN	NOM	MAX
A	4.40	4.55	4.72	0.173	0.179	0.186	L	1.94	2.30	2.60	0.076	0.091	0.102
A1	0.00	0.10	0.25	0.000	0.005	0.010	L3	1. 17	1.29	1.40	0.046	0.051	0.055
A2	2.59	2.69	2.79	0.102	0.106	0.110	L1	*	*	1.70	*	*	0.067
b	0.76	*	0.90	0.030	*	0.035	L4		0.25 BSC			0.01 BSC	
b1	1.22	*	1.36	0.048	*	0.054	L2		2.50 REF			0.098 REF	}
С	0.33	*	0.47	0.013	*	0.019	θ	0°	*	8°	0°	*	8°
c1	1.22	*	1.32	0.048	*	0.052	θ1	5°	7°	9°	5°	7°	9°
D	8.60	*	9. 29	0.339	*	0.366	θ2	1°	3°	5°	1°	3°	5°
E	9.95	*	10.26	0.392	*	0.404	DEP	0.05	0.10	0.20	0.002	0.004	0.008
е		2.54BSC			0.100BSC		Фр1	1.40	1.50	1.60	0.055	0.059	0.063
Н	14.70	15.10	15. 79	0.579	0.594	0.622							

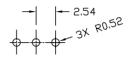


Package Information

TO220 PACKAGE OUTLINE



RECOMMENDATION OF HOLE PATTERN



UNIT: mm

- NOTE

 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
 MOLD FLASH SHOULD BE LESS THAN 6 MIL.

 2. TOLERANCE 0.100 MILLIMETERS UNLESS OTHERWISE SPECIFIED.

 3. CONTROLLING DIMENSION IS MILLIMETER.
 CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES				
SYMBOLS	MIN	NOM	MAX	MIN	NDM	MAX	
A	4,30	4,45	4.72	0.169	0,175	0,186	
A1	1.15	1.27	1.40	0.045	0.050	0.055	
A2	2.20	2.67	2.90	0.087	0,105	0.114	
b	0.69	0.81	0.95	0.027	0.032	0.037	
b2	1.17	1.37	1.45	0.046	0.050	0.068	
С	0.36	0.38	0.60	0.014	0.015	0.024	
D	14.50	15.44	15,80	0.571	0.608	0.622	
D1	8.59	9.14	9.65	0.338	0,360	0,380	
D2	11.43	11.73	12.48	0.450	0.462	0,491	
е		2.54 BS0	,	0.100 BSC.			
E	9.66	10.03	10.54	0.380	0,395	0,415	
E1	6.22			0.245			
H1	6.10	6.30	6.50	0.240	0.248	0,256	
L	12.27	12.82	14.27	0.483	0.505	0,562	
L1	2.47		3.90	0.097		0.154	
L2			16.70			0.657	
Q	2.59	2.74	2.89	0.102	0.108	0.114	
ØΡ	3.50	3.84	3.89	0.138	0.151	0.153	
Q1	2.70		2.90	0.106		0.114	



Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245 ℃ ±5 ℃	5sec±1sec
Pb-Free device	260℃+0/-5℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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